



TEST HATS:

The Haigh-Farr Test Hats enable communication while containing the RF energy from an antenna.

Haigh-Farr test hats are constructed out of a solid aluminum, one-piece case with a conductive EMI gasket where the hat is in contact with the ground plane and the antenna. This provides a tight EMI seal, minimizing RF leakage, typically to -80 dB or lower.

The coupling factor is a design parameter; however, it ranges from 4 dB to 30 dB, with each hat calibrated.

Haigh-Farr hats are designed to work with single or multiband Flexislot™ and Patch antennas, as well as single or multi-channel Wraparound™ antennas.

APPLICATIONS:

- Contain RF energy
- Ground and lab testing
- Reduced EMI environments
- System verification
- Late stage testing with last minute removal prior to flight

FEATURES:

- Tight EMI seal; leakage typically -80 dB or lower
- Frequencies from UHF to Ka-Band
- Single or multi-band designs
- Precision fit enables repeatable electrical characteristics when mating/demating
- Secure fastening. Flange designed to naturally mate to cylindrical, conical, and curved surfaces
- SMA, TNC, and other connector options available
- Low outgassing materials utilized
- Unique mounting techniques available



CUSTOM ANTENNA DESIGN

Haigh-Farr designs custom antennas to meet customer specifications.



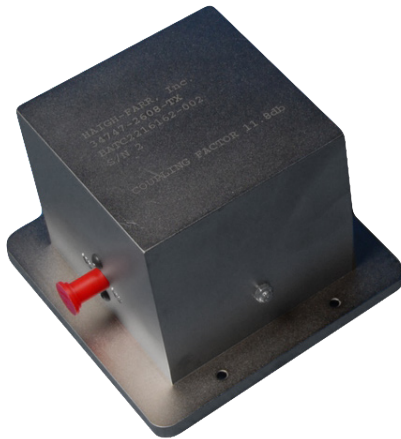
LEVERAGE EXISTING DESIGNS

Haigh-Farr can take an existing design and customize it to meet your application, saving NRE dollars and design time.



IN-HOUSE CAPABILITIES

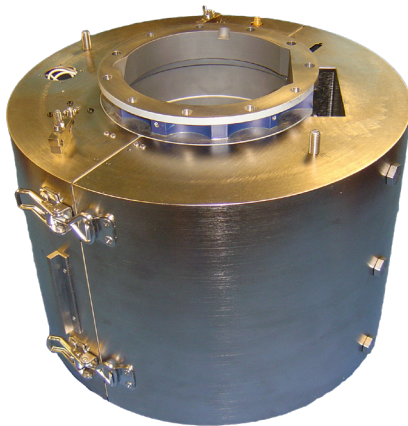
Manufacturing & testing is done in-house.



Single Channel Hat



Tri-Band Flexislot™ Hat



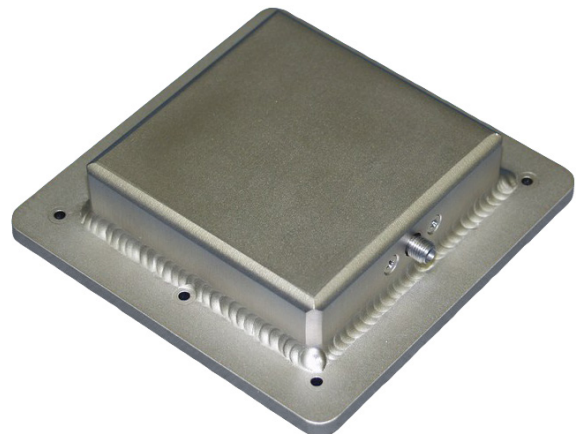
Tri-Band Hat



Tri-Band Flexislot™ Hat



Single Channel Hat



Tri-Band Flexislot™ Hat